

Surface Mount Multilayer Varistors

Product Identification

MLV 0402 ES 012V 0100 N T
 (1) (2) (3) (4) (5) (6) (7)

- (1) Series Code:
 MLV - Surface Mount Multilayer Varistor
 MVA-- MLV Array
 MVF-- ESD-EMI Filter
- (2) Size Code:
 Standard EIA Chip Size
- (3) Application Code:
 ES - Electro-static Discharge Protection
 NA - Normal Surge Protection
 HA - High Surge Protection
 L4 -- 4 lines
- (4) Max. Working Voltage:
 012V - 12V
- (5) Capacitance for ES Series:
 0100 - 100 pF
 02R5 - 2.5 pF
 Peak Current for HA/NA Series: 0100 - 100 A
- (6) Capacitance Tolerance for ES Series:
 N - $\pm 30\%$
 P - Special
- (7) Packaging Code:
 T - Tape & Reel
 B - Bulk

Operating Temperatures:

- 55°C to +85°C for size 0603 or smaller
- 55°C to +125°C for size 0805 or larger

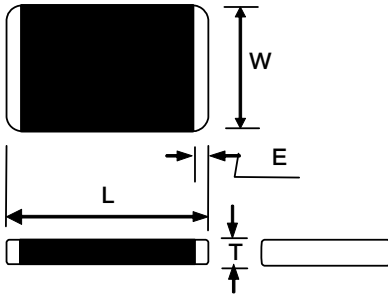
Terms and Definitions

Term	Definition
Max. Working Voltage	Maximum steady-state DC operating voltage with typical leakage current less than 50 μ A at 25° C
Varistor Voltage BDV	Breakdown DC voltage measured at current of 1 mA
Max. Clamping Voltage	Maximum peak voltage across the part, measured at a specified pulse current and waveform
Surge Current	Maximum peak current with the specified 8/20 s waveform without damage
Surge Shift V/V	The change of varistor voltage after applying the specified surge current
Energy Absorption	Maximum energy dissipated with a specified 10/1000 μ s waveform without damage
Typical Capacitance	Capacitance measured with voltage bias less than 0.5 V _{RMS} at 1 KHz or 1 MHz
Nonlinear Exponent	$a = (\log(V_{1mA}/V_{0.1mA}) / \log(I_{V1mA}/I_{V0.1mA}))$
Leakage Current	Typical leakage current at 25° C < 50 μ A; Maximum leakage 200 μ A.
Cut-off Frequency	The frequency of -3 dB insertion loss

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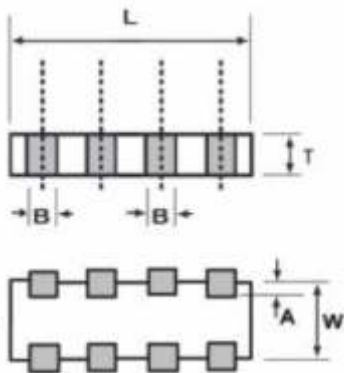
Shape and Dimensions

MLV Series



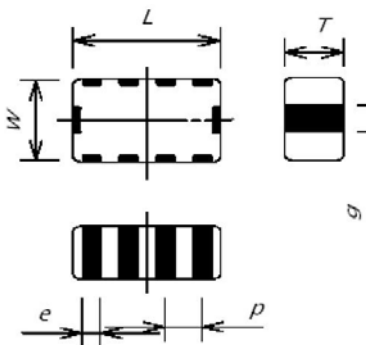
Size	L (mm)	W (mm)	T (mm)	E (mm)
0201	0.60 ± 0.03	0.30 ± 0.03	0.30 ± 0.03	0.30 ± 0.03
0402	1.00 ± 0.10	0.50 ± 0.10	0.50 ± 0.10	0.25 ± 0.10
0603	1.60 ± 0.15	0.80 ± 0.15	0.90 max.	0.30 ± 0.10
0805	2.00 ± 0.20	1.25 ± 0.15	1.00 max.	0.30 ± 0.10
1206	3.20 ± 0.20	1.60 ± 0.15	1.20 max.	0.50 ± 0.20
1210	3.20 ± 0.20	2.50 ± 0.20	1.50 max.	0.50 ± 0.20
1812	4.50 ± 0.20	3.20 ± 0.20	2.00 max.	0.60 ± 0.20
2220	5.70 ± 0.20	5.00 ± 0.20	3.00 max.	0.60 ± 0.20

ESD Array



Size	0508	0612
L (mm)	2.00 ± 0.20	3.20 ± 0.20
W (mm)	1.25 ± 0.20	1.60 ± 0.15
T (mm)	0.80 max.	0.95 max.
A (mm)	0.20 ± 0.10	0.20 ± 0.10
B (mm)	0.25 ± 0.05	0.40 ± 0.15

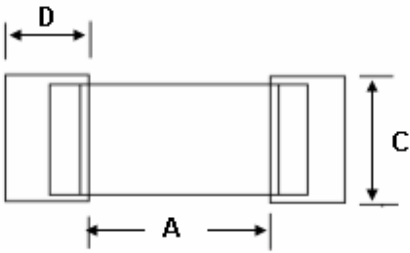
ESD-EMI Series



Size	L (mm)	W (mm)	T (mm)	e (mm)	p (mm)	g (mm)
508	2.00 ± 0.2	1.25 ± 0.2	0.75 ± 0.1	0.25 ± 0.1	0.50	0.25 ± 0.15

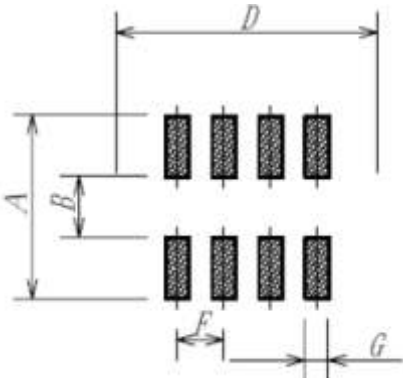
Recommended Land Patterns

MLV Series



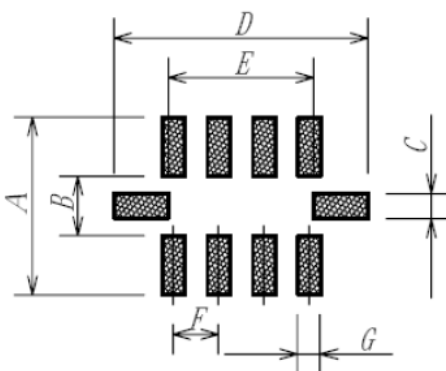
Size	Solder pad layout		
	A (mm)	C (mm)	D (mm)
0201	0.25~0.35	0.20~0.30	0.25~0.35
0402	0.4~0.6	0.5~0.6	0.5~0.7
0603	0.9~1.2	0.6~1.0	0.8~1.2
0805	1.0~1.5	1.2~1.5	1.0~1.4
1206	1.8~2.5	1.2~1.8	1.0~1.4
1210	1.8~2.5	2.2~3.0	1.0~1.4
1812	2.5~3.3	2.8~3.6	1.2~1.8
2220	3.8~4.6	4.8~5.5	1.2~1.8

ESD Array Series



Size	A (mm)	B (mm)	D (mm)	F (mm)	G (mm)
0508	2.10	0.40	2.50	0.50	0.35
0612	2.60	0.80	3.60	0.80	0.50

ESD-EMI Series



Size	A (mm)	B (mm)	C (mm)	D (mm)	E (mm)	F (mm)	G (mm)
0508	2.00	0.60	0.25	2.50	1.60	0.50	0.25

Environmental Tests

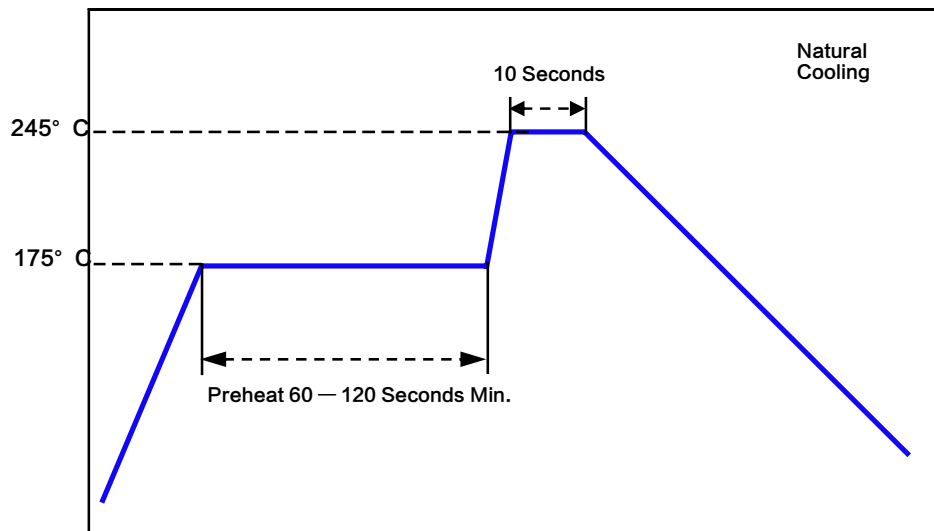
No.	Test	Requirement	Test condition	Test reference
1	Soldering heat resistance	BDV change $\leq \pm 10\%$ No mechanical damage	One dip at 260°C for 5 sec.	MIL-STD-202 Method 210 IEC 60068-2-20
2	Solderability	New solder coverage $\geq 80\%$	One dip at 255°C for 5 sec. Non-active flux	MIL-STD-202 Method 208 IEC 60068-2-20
3	Maximum surge current	BDV change $\leq \pm 10\%$ No mechanical damage	100 pulses of 8/20 μ s with maximum surge current and 30 interval at 25°C and 30~65 % RH	CECC 42000 IEC 1051-1 Test 4.5
4	Maximum surge energy	BDV change $\leq \pm 10\%$ No mechanical damage	100 pulses of 10/1000 μ s with maximum surge current and 90 interval at 25°C and 30~65 % RH	CECC 42000
5	Thermal cycling	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	5 cycles between -40°C and 125°C with 30 min. dwell time at the temperature extremes and 60 dwell time at 25°C	CECC 42000 IEC 60068-2-14
6	Low temperature resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	1000 hr at -50°C	IEC 60068-2-1
7	Low temperature load resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	1000 hr at -50°C with working voltage applied	IEC 60068-2-1
8	High temperature resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	1000 hr at 150°C	MIL-STD-202 Method 108 CECC 42000
9	High temperature load resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	1000 hr at 85°C with working voltage applied	CECC 42000
10	Humidity resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	500 hr at 40°C and 90 ~ 95 % RH	MIL-STD-202 Method 103 IEC 60068-2-3 CECC 42000;
11	Humidity load resistance	BDV change $\leq \pm 10\%$ No mechanical damage Leakage current $\leq 200\mu$ A	500 hr at 40°C and 90 ~ 95 % with working voltage applied	MIL-STD-202 Method 103 IEC 60068-2-3 CECC 42000
12	ESD contact test*	Varistor voltage change $> 115\%$ working voltage	Contact electrostatic discharge times with 1 second intervals at 8 KV (Level 4) and polarity: +,-	IEC 61000-4-2
13	ESD air test *	Varistor voltage change $> 115\%$ working voltage	Air contact electrostatic discharge times with 1 second intervals at 15 KV (Level 4) and polarity: +,-	IEC 61000-4-2

For ES series only.

Surface Mount Multilayer Varistors

Soldering Temperature Profile

Recommended Temperature Profile
for Reflow Soldering



Recommended conditions for hand soldering:

1. Appropriate temperature (max.) of soldering iron tip/soldering time (max.): 280° C /10 s or 350° C /3 s
2. Using hot air rework station with tip that can melt the solder on both terminations at the same time is strongly recommended. Do not directly contact the chip termination with the tip of soldering iron.